Se	arch N	otes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/092,028	DEGEN ET AL.	
Examiner	Art Unit	
Sara Chandler	3693	

	SEAR	CHED	
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
705	39	7/1/07	Smc

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
East- foreign databases	7/1/2007	SMC
STIC- Business Method templates, NPL, foreign	6/20/2007	SMC